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(54) Title: A METHOD OF PROVIDING A VERTICAL INTERCONNECT BETWEEN THIN FILM MICROELECTRONIC DEVICES

## (57) Abstract

A simple and reliable method of providing a vertical interconnect between thin-film microelectronic devices is provided. In said method, a tool tip (20) is used to make a notch (104) in a vertical interconnect area (100) of two organic electrically conducting areas (3, 6) separated from each other by an organic electrically insulating area (5). The method is used in the manufacture of integrated circuits consisting substantially of organic materials.

